Search Notes					

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/711,637	CHEN ET AL.	
Examiner	Art Unit	
Tsz K. Chiu	2822	

	SEAR	CHED	
	027.11		
Class	Subclass	Date	Examiner
257	49	1/20/2006	ткс
257	66-67	1/20/2006	TKC
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INT	ERFERENC	E SEARCH	ED
Class	Subclass	Date	Examiner

SEARCH NOT (INCLUDING SEARCH	TES STRATEGY)
	DATE	EXMR
EAST (text search see attach)	1/20/2006	ткс
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